

<b>Interview Summary</b>	Application No.	Applicant(s)
	10/632,755	WEIRAUCH, CHARLES R.
	Examiner Esaw T. Abraham	Art Unit 2133

All participants (applicant, applicant's representative, PTO personnel):

(1) Esaw T. Abraham. (3) \_\_\_\_\_

(2) Augustus Winfield. (4) \_\_\_\_\_

Date of Interview: 14 June 2006.

Type: a) Telephonic b) Video Conference  
c) Personal [copy given to: 1) applicant 2) applicant's representative]

Exhibit shown or demonstration conducted: d) Yes e) No.  
If Yes, brief description: \_\_\_\_\_.

Claim(s) discussed: None.

Identification of prior art discussed: None.

Agreement with respect to the claims f) was reached. g) was not reached. h) N/A.

Substance of Interview including description of the general nature of what was agreed to if an agreement was reached, or any other comments: The Examiner called Attorney Ausgustus Winfield in reference to a restriction requirement, the Attorney requested that the application is expressly abandoned.

(A fuller description, if necessary, and a copy of the amendments which the examiner agreed would render the claims allowable, if available, must be attached. Also, where no copy of the amendments that would render the claims allowable is available, a summary thereof must be attached.)

THE FORMAL WRITTEN REPLY TO THE LAST OFFICE ACTION MUST INCLUDE THE SUBSTANCE OF THE INTERVIEW. (See MPEP Section 713.04). If a reply to the last Office action has already been filed, APPLICANT IS GIVEN A NON-EXTENDABLE PERIOD OF THE LONGER OF ONE MONTH OR THIRTY DAYS FROM THIS INTERVIEW DATE, OR THE MAILING DATE OF THIS INTERVIEW SUMMARY FORM, WHICHEVER IS LATER, TO FILE A STATEMENT OF THE SUBSTANCE OF THE INTERVIEW. See Summary of Record of Interview requirements on reverse side or on attached sheet.

3. (Currently Amended) A liquid crystal display device comprising:  
gate lines arranged to cross data lines on a substrate, thereby defining a pixel region;  
thin film transistors, each having a gate electrode and source and drain electrodes,  
formed at crossing points of the gate lines and the data lines;  
a contact hole formed over the drain electrode and the pixel region; and